

Search Notes**Application/Control No.**

10/654,761

Examiner

Mark K. Han

Applicant(s)/Patent under Reexamination

AUSIELLO ET AL.

Art Unit

3767

SEARCHED

Class	Subclass	Date	Examiner
604	890.1	4/27/2006	meh
	891.1		
	892.1		
	27 514		
	515 93.01		
	131 245		
	247 265		
424	430		
	432		
	433		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name search	11/14/2005	meh
EAST text search	4/27/2006	meh

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner